Artificial Intelligence for Cybersecurity

Guest Editor:

Dr. Amani S. Ibrahim
School of Information Technology, Deakin University, Geelong, VIC, Australia

Deadline for manuscript submissions:
closed (30 October 2021)

Message from the Guest Editor

Artifial Intelligence (AI) and Machine Learning (ML) has taken centre stage in the cybersecurity industry indicating a clear trend in future cyber defence technologies. This Special Issue is dedicated to publishing cutting-edge research focused on addressing the various fundamental technical open challenges related to implementing AI\ML in the area of cybersecurity to discuss the hype around the ability of AI-powered solutions that claim to "do it all."

- Topics of interest include the following:
- Artificial intelligence and machine learning for cybersecurity
- Threat intelligence and AIOps
- Data intellgeince and DataOps
- Preventing security and data breaches
- Risk management and threat management
- Security operation centers management and challenges
- Threat landscape prediction
- Adversairal machine learning
- Threat and risk modelling
- Log management
- IoT security
- Mobile Security
- Network Security
- Enterprise security

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Special Issue

Editor-in-Chief

Prof. Dr. Flavio Canavero
Department of Electronics and
Telecommunications,
Politecnico di Torino, 10129
Torino, Italy

Message from the Editor-in-Chief

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